



Encyclopedia of Statistics in Quality and Reliability

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DESCRIPTION

An essential reference for statisticians, engineers, and quality professionals in industry, academia, and government, *Encyclopedia of Statistics in Quality and Reliability* offers an essential knowledge source in an area where one is sorely needed. Providing a practical orientation with a large selection of case studies, this multi-volume state-of-the-art publication examines the widespread use of Six Sigma. This popular quality measuring technique is a highly adaptable tool with many wide-reaching applications in a large variety of sectors.

ABOUT THE AUTHOR

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Fabrizio Ruggeri, CNR-IMATI, Milan, Italy Prof. Ruggeri's research interests include reliability, general statistical modelling with applications in industry, and Bayesian statistics. He is a former President of the European Network for Business and Industrial Statistics (ENBIS) and former Board member of the International Society for Bayesian Analysis (ISBA). He edited two volumes on Bayesian Robustness and special issues of journals. He also served as the Editor (1999-2002) of the ISBA Bulletin and is currently Editor-in-Chief of Applied Stochastic Models in Business and Industry and an Editor of Bayesian Analysis. He is Co-Director of the Applied Bayesian Statistics summer school (ABS) and Chair of the Scientific Committee of the Bayesian Inference in Stochastic Processes (BISP) series of workshops. He is a faculty in the Ph.D. programme in Mathematics and Statistics at the University of

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Ron S. Kenett, KPA Ltd, Raanana, Israel and University of Turin, Turin, Italy. Professor Kenett's interests include Strategic Planning and Quality Management, Industrial Statistics and Biostatistics, Statistical Process Control and Design of Experiments, Survey Methodology and Software Quality. He is a Fellow of the Royal Statistical Society, a Senior Member of the American Society for Quality, past member of the board of the Israeli Statistical Association and past president of ENBIS, the European Network for Business and Industrial Statistics. He is editor in chief of the journal Quality Technology and Quantitative Management and associate editor of the Journal of the Royal Statistical Society (A) and Applied Stochastic Models in Business and Industry. He is co author of 4 books and over 130 papers, including Modern Industrial Statistics (with S. Zacks), Duxbury Press 1998, and Software Process Quality - Management and Control (with E. Baker) Marcel Dekker Inc., 1999. Ron has been a consultant for leading corporations such as AT&T, hp, EDS, SanDisk, IBM and Amdocs. His career has combined academic positions with activity in the industrial and business sector.

Frederick W. Faltin, The Faltin Group, Cody, WY, USAMr. Faltin's interests include Managing Six Sigma, Design for Six Sigma, Business Process Simulation & Optimization, Financial Quality, Supply Chain Management, and Design of Experiments. He is a Fellow of the American Statistical Association, a recipient of the Shewell Prize of the American Society for Quality, and has served on the selection committees of various ASQ awards. He served on the Editorial Review Board of the Journal of Quality Technology, is a past Chair of ASA's Quality and Productivity Section, and is a member of the boards of the Quality & Productivity Research Conference and the Fall Technical Conference. Mr. Faltin has published dozens of papers on applications of mathematics & statistics, and has authored Six Sigma curricula for a number of prominent companies, including Motorola—the company that invented Six Sigma. He was formerly manager of the Strategic Enterprise Technologies laboratory at GE's Global Research Center, and is today Managing Director of The Faltin Group, which he founded in 1999.

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